



IEEE SW Test Workshop

Semiconductor Wafer Test Workshop

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High Performance Spring Probe and 0.35mm pitch Elastomeric Contact by Stamping Process



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Overview

- **Various spring probes by stamping**
- **Major strengths of stamped pin**
- **Case studies for HPSP2821**
- **Insertion loss, Cres, Current carrying**
- **Elastomeric contact by stamping**
- **Challenges and Solution**
- **Summary for stamped elastomeric contact**

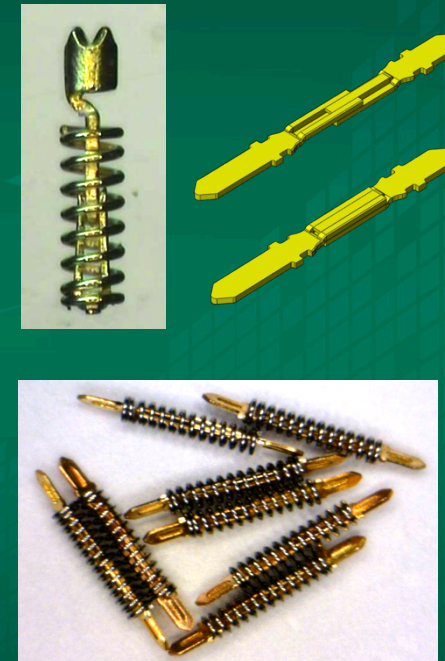


Various Spring Probes by Stamping

One Piece Spring Probes

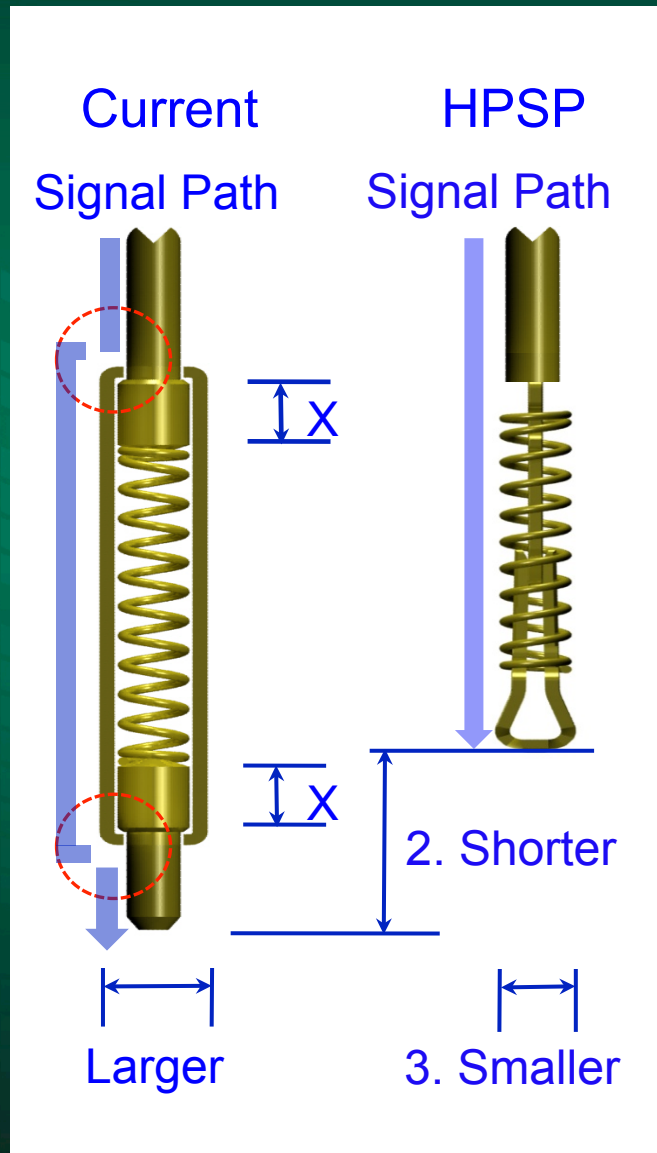


Three Pieces Spring Probes



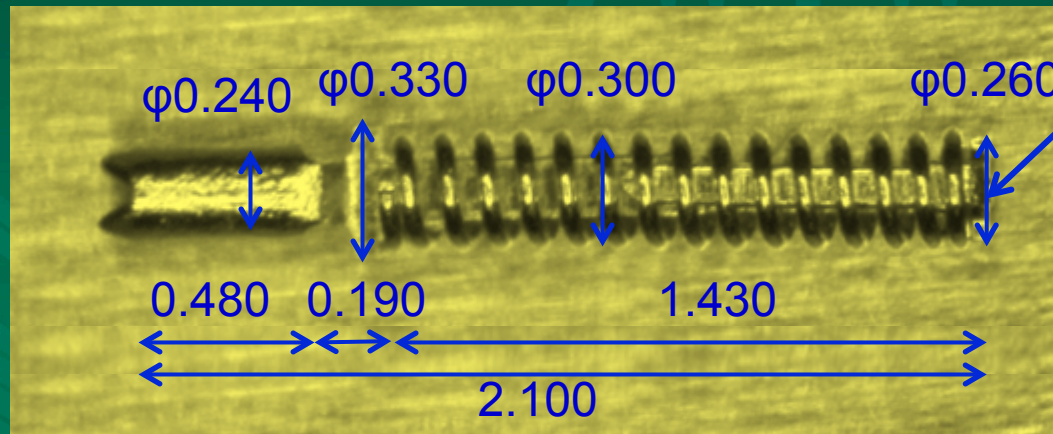
Note : Refer to SWTW 2012 presentation for details and how to make

What are the major differences ?



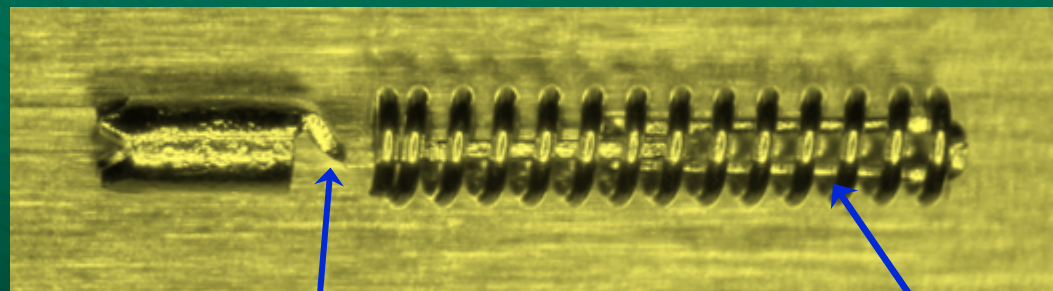
1. Stable Signal path by pinched sliding
2. Enabling Short length, 1.2mm, good for high speed application
3. Enabling Small diameter, good for finer pitch, 0.2mm pitch
4. High current carrying, 4.5 Amps in 0.4mm pitch, 3.3mm length pin
5. 0.8mm traveling in 3.3 mm length
6. Progressive stamping enabling low cost

Appearance & size measurement



Projection

- $\phi 0.081\text{mm}$
- Height 0.01mm

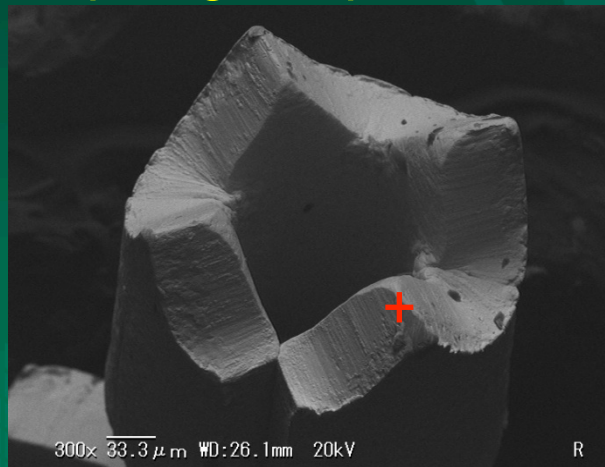


Thickness: 0.050

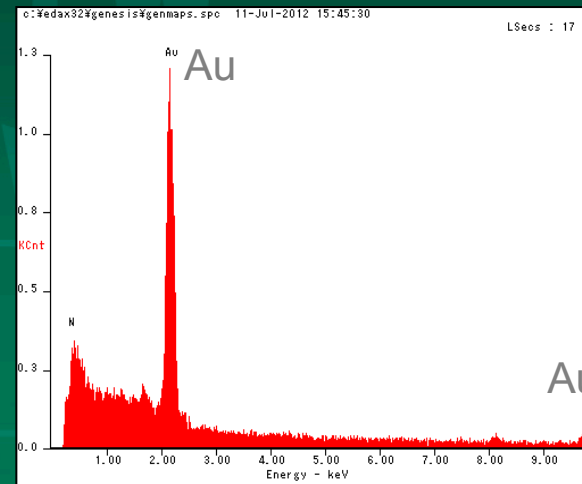
Thickness: 0.040

SEM & Componential Analysis Result

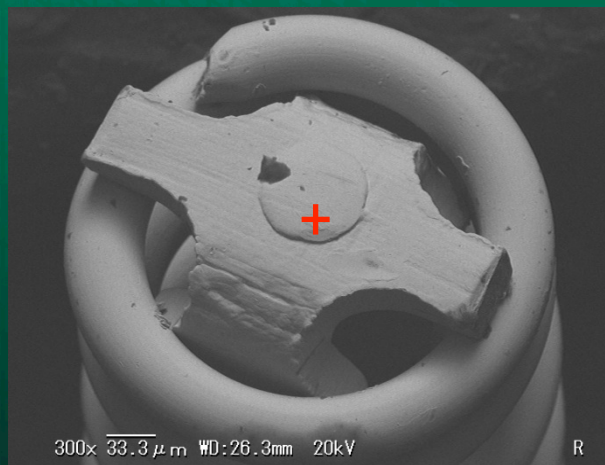
A-plunger Tip



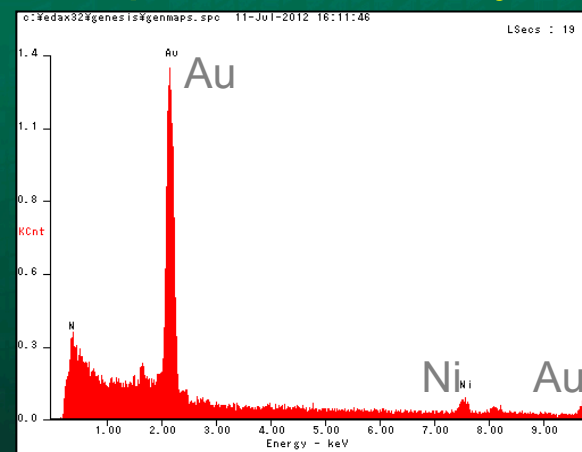
Componential analysis result



B-plunger Tip

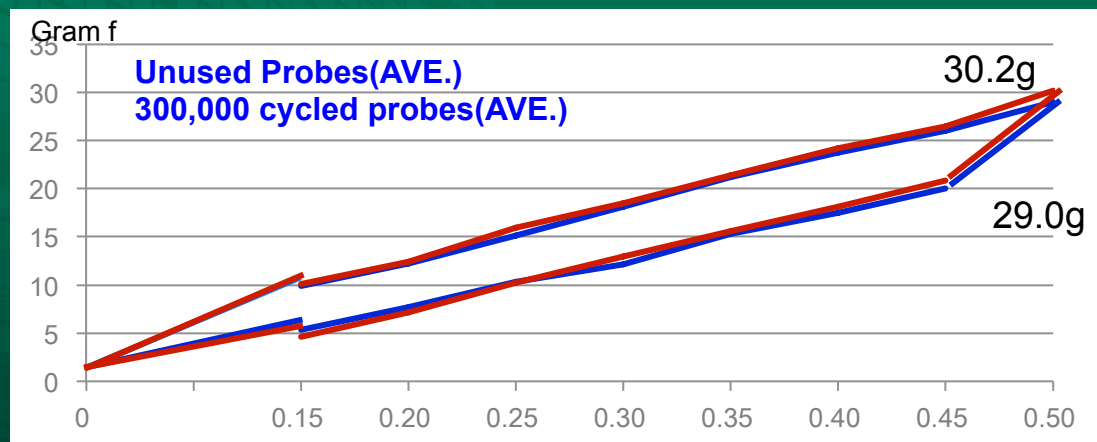
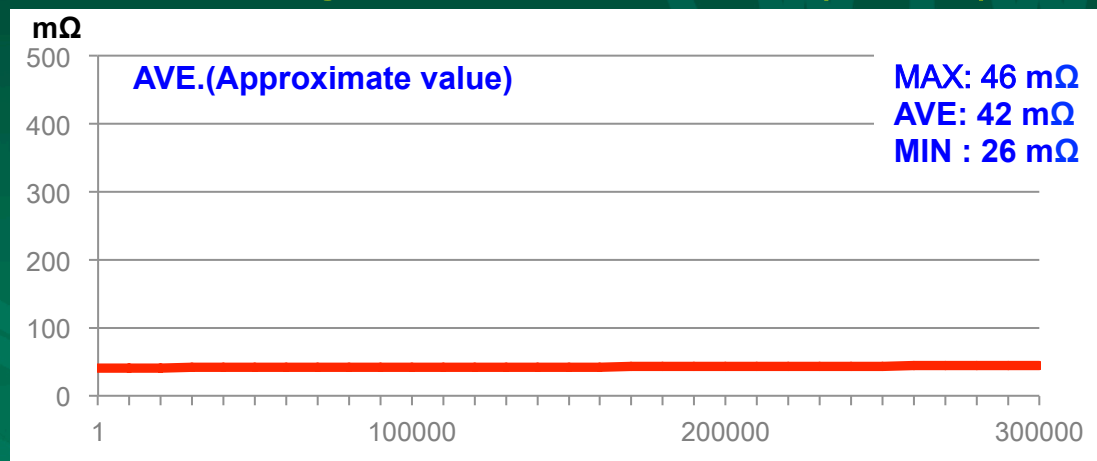


Componential analysis result



Durability test – 300k cycles

Spring force vs Stroke (n=20)



Test condition

- Cycles: 300,000 times
- Contacted electrode: Au plate
- Measure Resistance: Every 10,000 times
- Stroke: 0.50mm (Pre-stroke: 0.15mm)

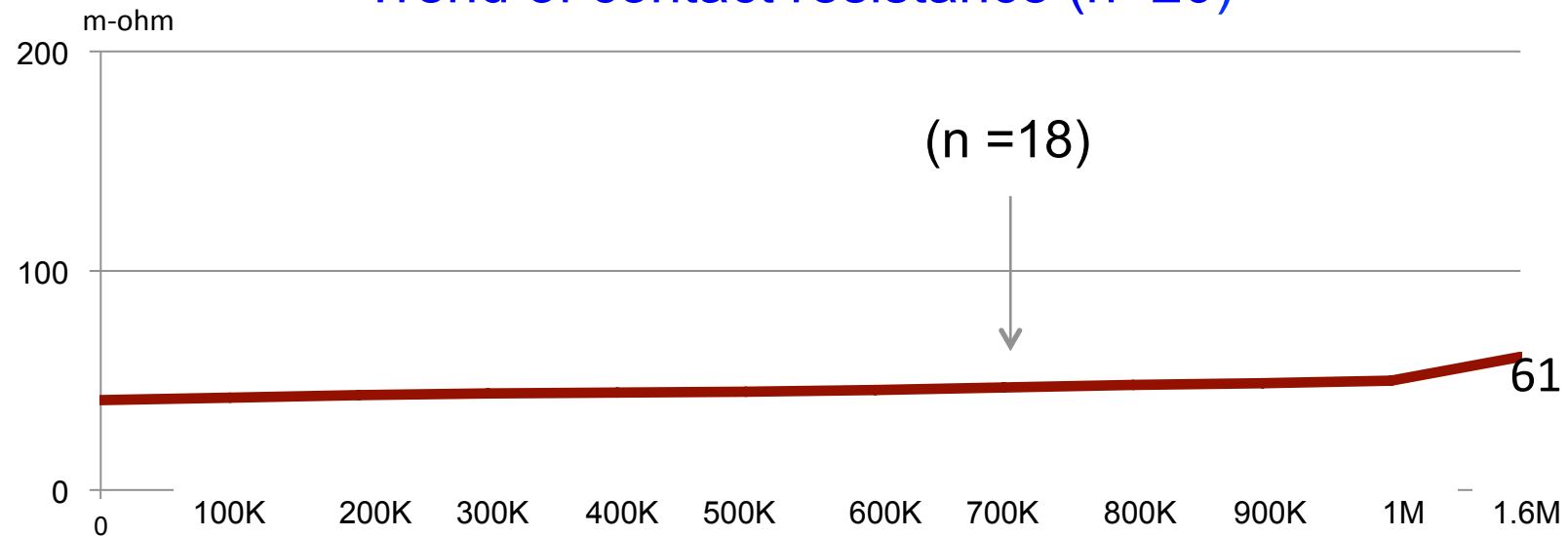
Pre-stroke; 0.15mm



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Destructive test

Trend of contact resistance (n=20)



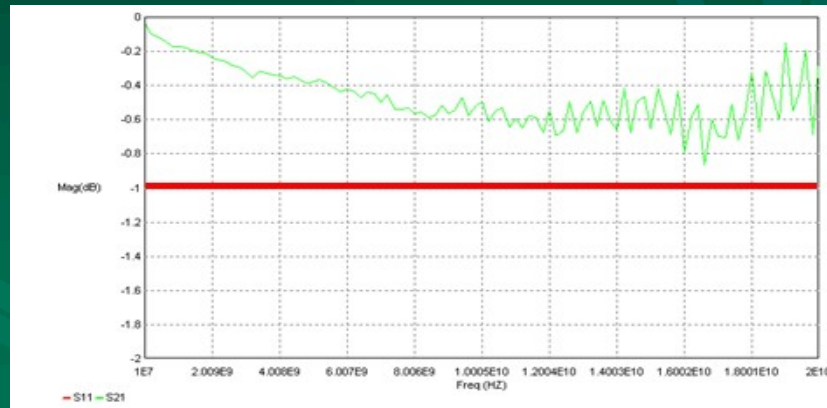
Cycles	Condition	To improve
700 k	Deflection of spring	Safety ratio shall be increased
>1 M	Erosion of gold plating	Material shall be changed to special alloy, not requiring gold plating

Insertion Loss Test Data

Sample #1

Transmission 22.4GHz @-1 db

Reflection 3.2GHz @-20db



Sample #2

Transmission 21.3GHz @-1 db

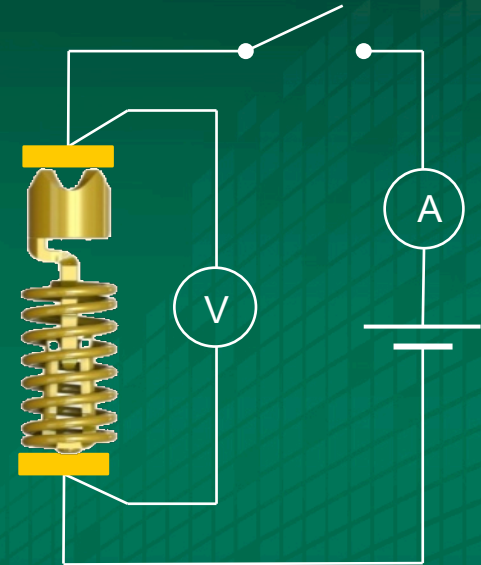
Reflection 3.0GHz @-20db



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Current Carrying Capacity Measuring

- * Test condition: Ambient temp (25°C)
- * Test method: Started from 1Amp and increase 1 Amp by every one minute
- * Measure allowable current carrying:
 - Any change in contact force
 - Burn
 - Permanent deflection
- * Result
 - Contact force was changed at 5.0Amp
- * Conclusion
 - Acceptable for 3.5A of current carrying



Current Carrying Capacity Measuring

* Result

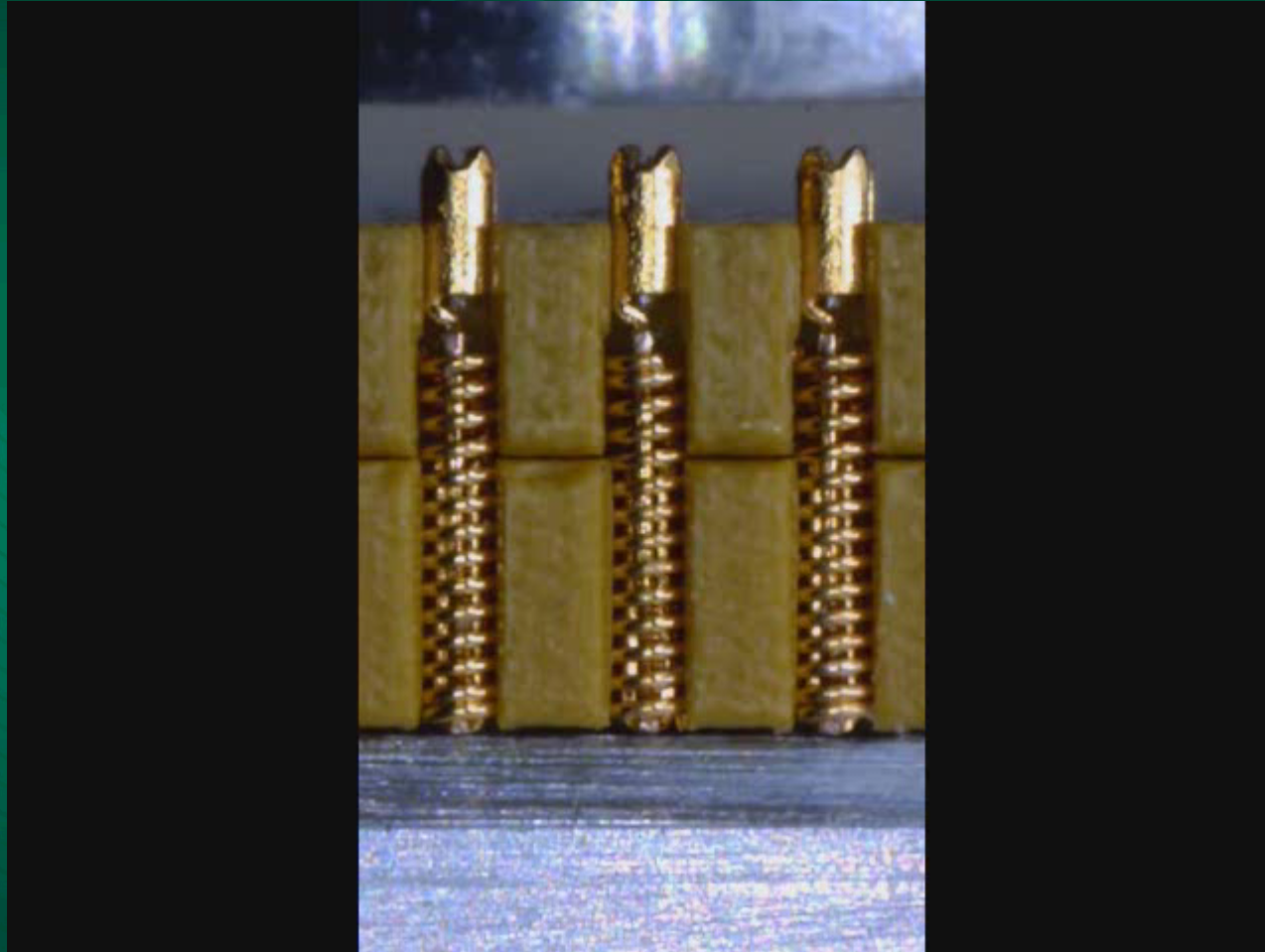
- in 4.5~5.0 Amp, contact force was changed

Current	Sample 1	Sample 2	Sample 3	Sample 4	Sample 5
1.0A	OK	OK	OK	OK	OK
1.5A	OK	OK	OK	OK	OK
2.0A	OK	OK	OK	OK	OK
2.5A	OK	OK	OK	OK	OK
3.0A	OK	OK	OK	OK	OK
3.5A	OK	OK	OK	OK	OK
4.0A	OK	OK	OK	OK	OK
4.5A	OK	C/F Changed	OK	OK	OK
5.0A	C/F Changed		C/F Changed	C/F Changed	C/F Changed



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HPSP2821 in motion



Available Tip Shape



Single



Double



Cylindrical
Crown



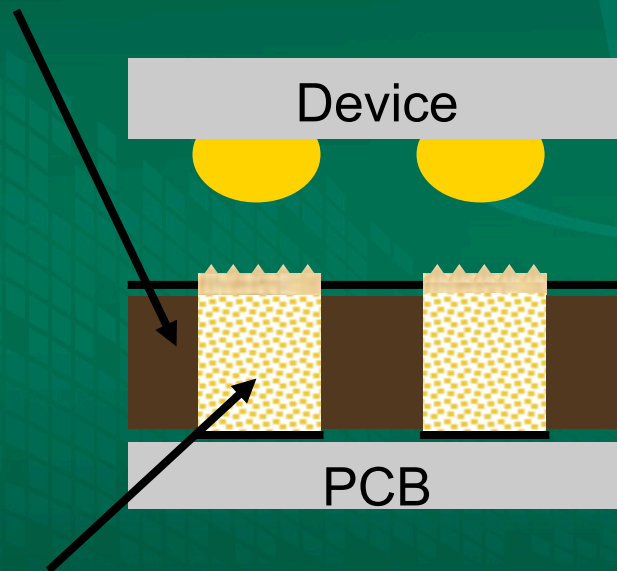
Cylindrical
Flat



Cylindrical
Sharpen

Previous concept of elastomer socket

Elastomer



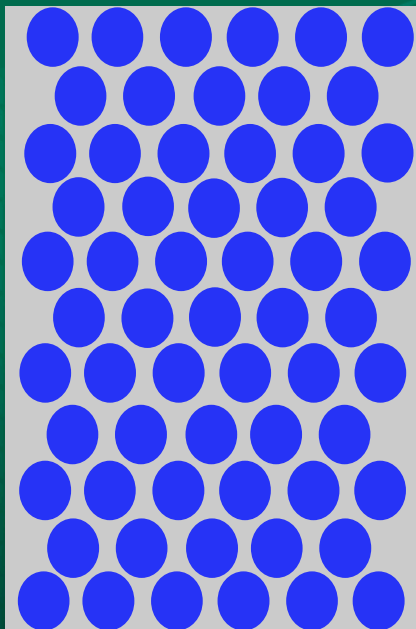
Conductive Particle
(Metal Powder)

- Simple socket structure
- Good for high frequency
- Wider contact area
- Least ball damage
- Less contamination



Electrical Conductivity vs Flexibility

High density
Conductive particle



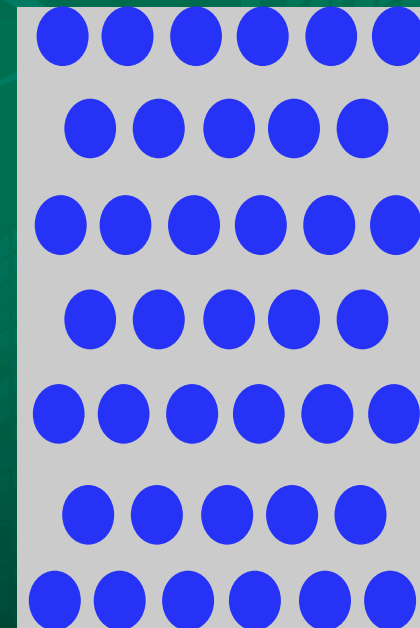
Electrical Conductivity

>

Flexibility

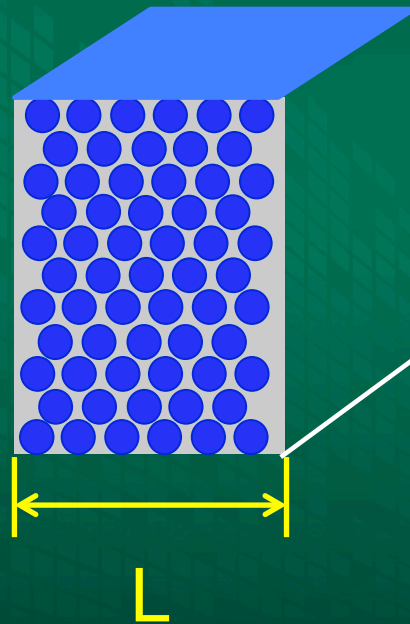
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Low density
Conductive particle

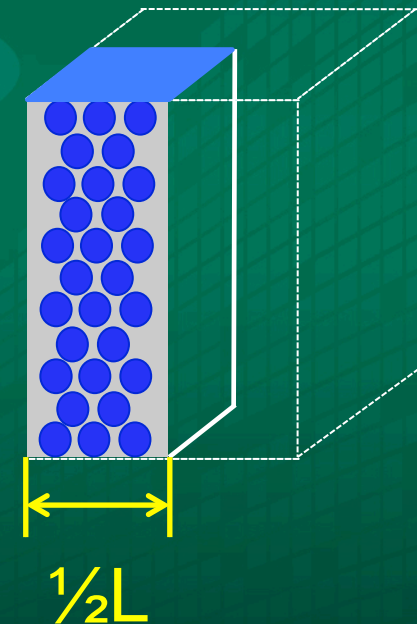


Resistance at fine pitch

Pitch 0.5mm→0.4mm, Pad size 0.38 mm→ 0.28 mm
Electrical resistance increased by two times



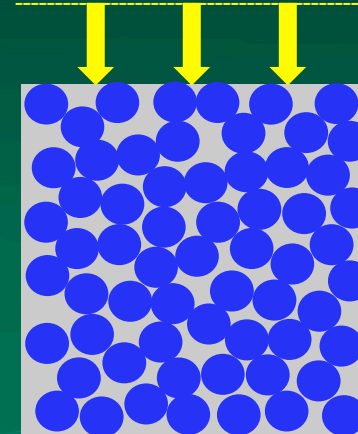
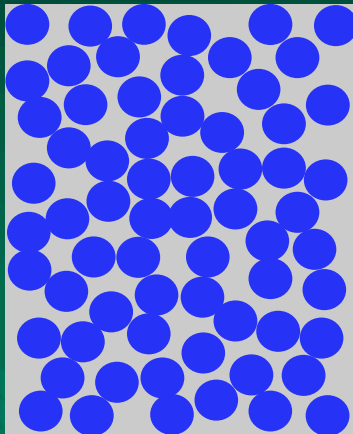
$L \rightarrow \frac{1}{2}L$,
electrical conductive
reduce to $\frac{1}{4}$



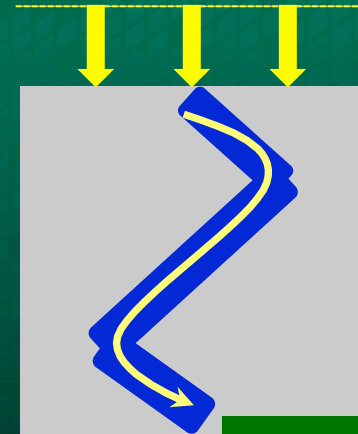
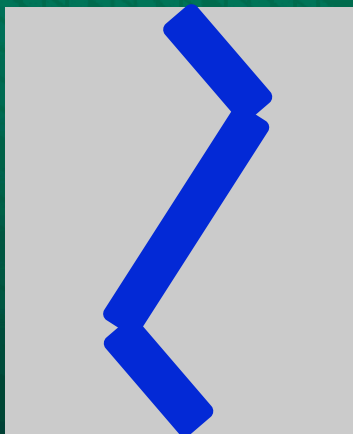
New Idea



Conductive particle



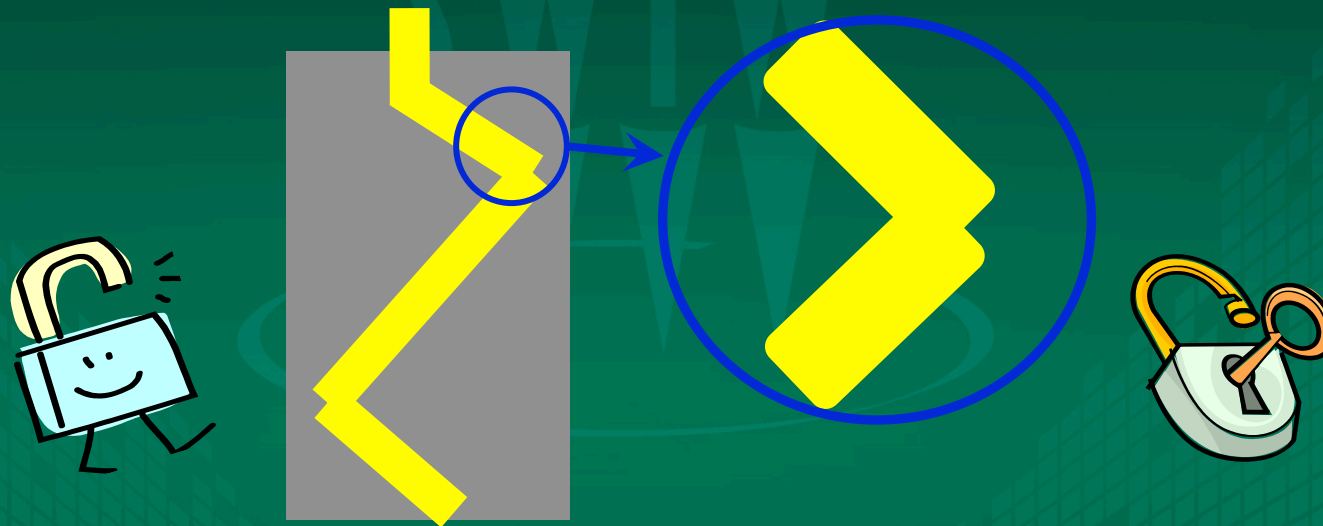
Metal Strip



Signal path



How to eliminate rigidity of metal structure



Progressive Stamping of metal strip → Heat treatment

→ Rubber injection (Coating) → metal parts separate in pieces by pressure from the top at v-notches → rigidity of metal parts eliminated

Rubber providing Spring force

Metal parts providing Signal path



What's the challenge ?

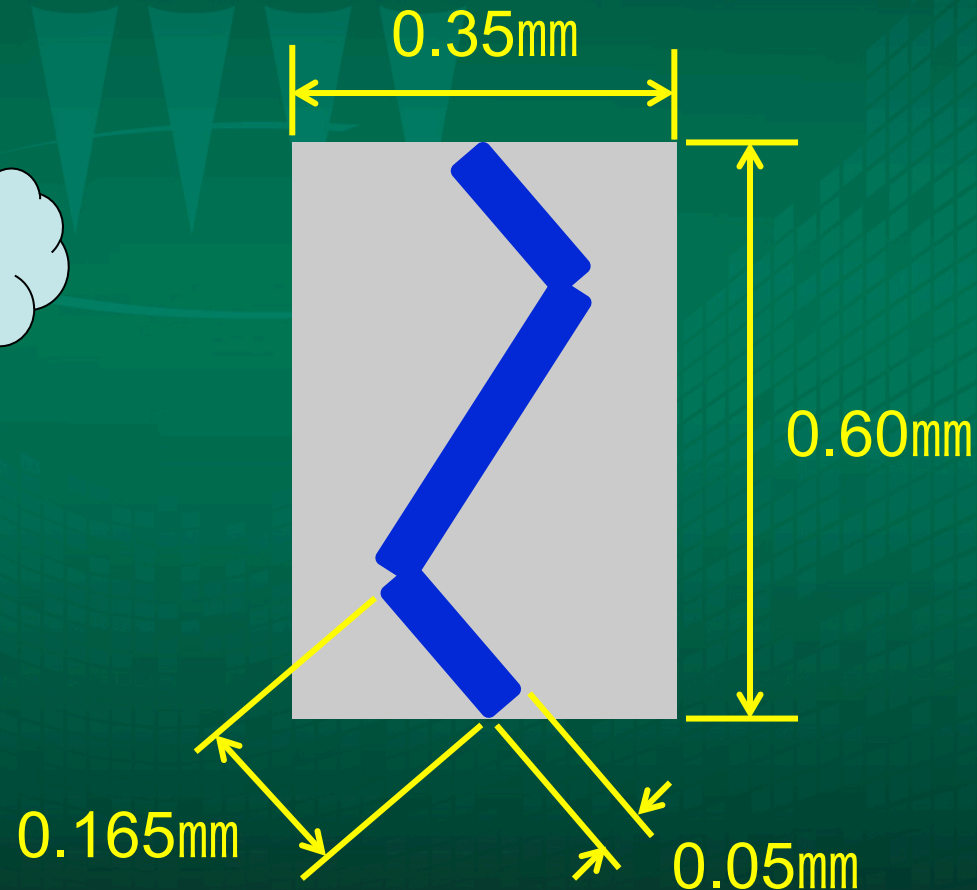
length 0.16mm x width 0.22mm

Numerous tiny metal pieces to be aligned in rubber

Possible

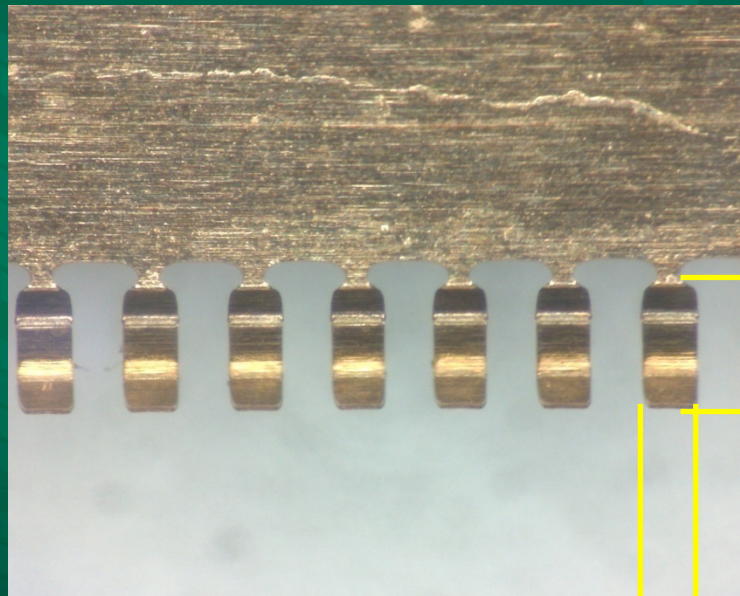


How



Stamped metal strip for a core metal

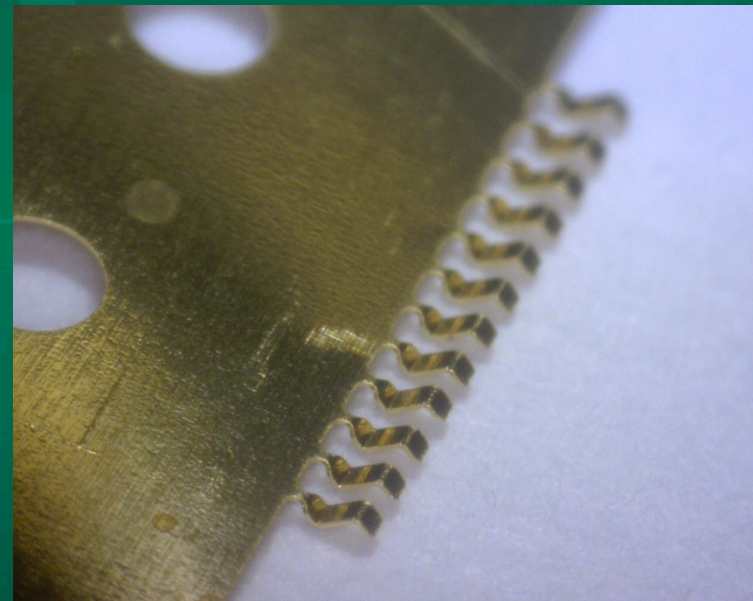
0.35mm pitch



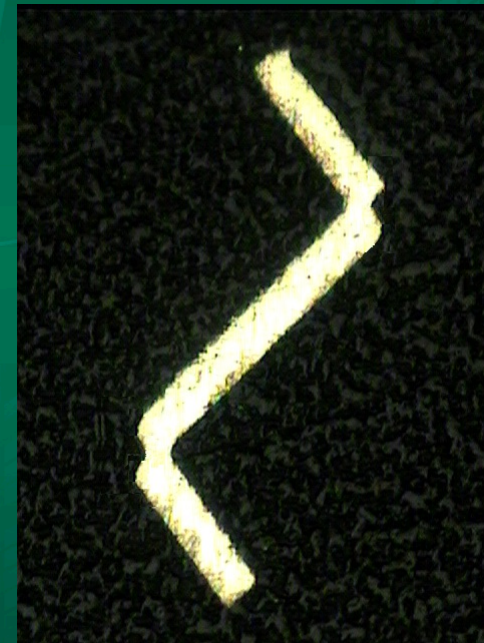
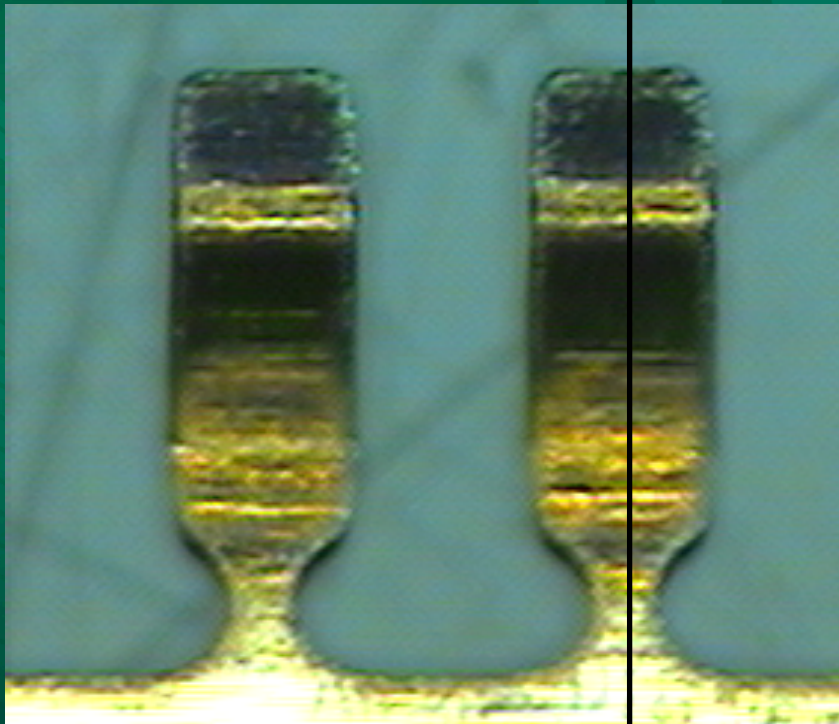
0.55mm

Thickness 0.04mm

0.22mm



V-notches at core metal piece

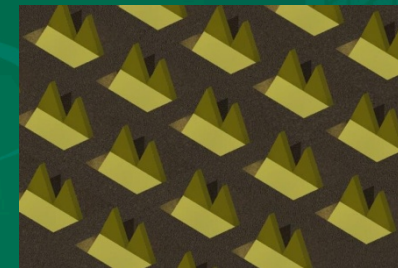
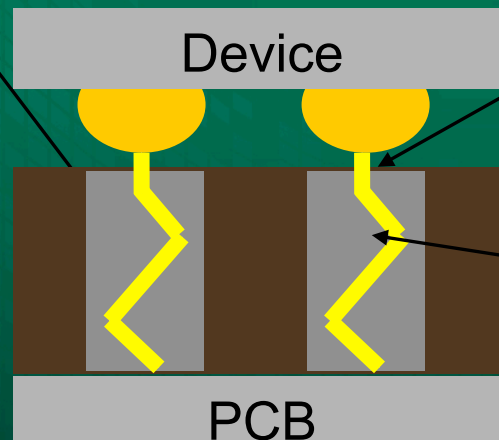


A-A Cross Section

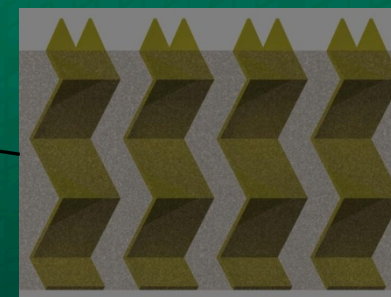
New design by core metal

- Signal path thru metal pieces
→ Better electrical performance
- Spring force by elastomeric
→ Good travelling

Elastomer



Upper probe tip



Core metal

Summaries for elastomeric contact by stamping

- Development expense funded by Korean Government
- Challenged 0.35 mm pitch and 0.6mm in thickness, providing 0.25mm travel
- Contact resistance 32 milii-ohm
- Insertion loss tested only up to -1db@40 GHz
- Need to find better rubber for improving low temperature performance

